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AMENDMENTS TO THE CLAIMS:

Claims 1-4 (Cancelled)

Claim 5. (Currently amended) A polishing apparatus comprising:

a turn table having a polishing surface;

a top ring for holding an object to be polished by said polishing surface;

*A¹
Cont'd*

and an end point detecting mechanism for informing operable to indicate an end point of polishing and to output a measured signal; and-

said end point detecting mechanism comprising:

~~counting means including a plurality of n-nary counters, and~~

~~gate means for supplying the measured signal to an input of said respective n-nary counters in order at given time intervals;~~

and a frequency measuring device, said frequency measuring device comprising

a plurality of n-nary counters, and

a plurality of gate circuits operable to receive the measured signal outputted by said end point detecting mechanism, and to supply the measured signal to an input of said plurality of n-nary counters, respectively, in a respective order at given time intervals.

wherein said frequency measuring device is operable to supply for supplying a frequency measurement result of the measured signal from said counting means said plurality of n-nary counters every given time interval.

*A
Cont'd*

Claim 6. (Currently amended) A polishing method for informing indicating an end point of polishing of an object to be polished by a turn table having a polishing surface, said method comprising:

providing ~~counting means~~ including a plurality of n-nary counters; and
supplying the a measured signal to a respective input of said plurality of n-nary counters in a respective order at given time intervals;
wherein a frequency measurement result of the measured signal is supplied from said ~~counting means~~ plurality of n-nary counters every given time interval.

Claims 7-18 (cancelled)

Claim 19. (New) A device for measuring a frequency of a measured signal, said device comprising:
a plurality of n-nary counters;
a plurality of gate circuits operable to supply the measured signal to an input of said plurality of n-nary counters, respectively, each of said plurality of gate circuits being operable to open in a respective order at a certain time interval;
a latch circuit operable to receive a signal from each of said plurality of n-nary counters, wherein a frequency measurement result of the measured signal is supplied from said plurality of n-nary counters.

*A
Cont'd*

Claim 20. (New) A method for measuring the frequency of a measured signal, said method comprising:

supplying a signal from a plurality of gate circuits, each of said plurality of gate circuits being operable to open in a respective order at a certain time interval; and

receiving said signal from each of said plurality of gate circuits by a latch circuit, said latch circuit being operable to output the signal in the respective order at a certain time interval.

Claim 21. (New) An apparatus for polishing a substrate, said apparatus comprising:

an end point detecting mechanism operable to detect an end point of polishing and to output a polishing information signal;

a frequency measuring device comprising a plurality of n-nary counters, each of said plurality of n-nary counters being operable to output a signal according to the polishing information signal, and said frequency measuring device being operable to measure the signal output by said plurality of n-nary counters.

Claim 22. (New) An apparatus in accordance with claim 21, wherein said frequency measuring device further comprises a plurality of gate circuits operable to receive the polishing information signal from said end point detecting mechanism and to supply the polishing information signal to said plurality of n-nary counters.

Claim 23. (New) An apparatus in accordance with claim 22, wherein each of said plurality of gate circuits opens in a respective order at a certain time interval.

Claim 24. (New) An apparatus in accordance with claim 23, wherein said frequency measuring device further comprises a latch circuit operable to receive the signal from each of said plurality of n-nary counters.

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cont'd*
Claim 25. (New) A polishing method, said method comprising:

providing a plurality of n-nary counters;

supplying a signal to said plurality of n-nary counters to be measured by said plurality of n-nary counters;

measuring a frequency of the signal measured by said plurality of n-nary counters; and
detecting an end point of polishing according to the frequency of the measured signal.

Claim 26. (New) A method of polishing a substrate, said method comprising:

providing a plurality of n-nary counters;

supplying a signal to said plurality of n-nary counters to be measured by said plurality of n-nary counters;

measuring a frequency of the signal measured by said plurality of n-nary counters; and
detecting a thickness of a layer formed on said substrate according to the frequency of the measured signal.

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end

Claim 27. (New) An apparatus for polishing a substrate, said apparatus comprising:
an end point detecting mechanism operable to detect an end point of the polishing; and
a measuring device comprising a plurality of counters.
